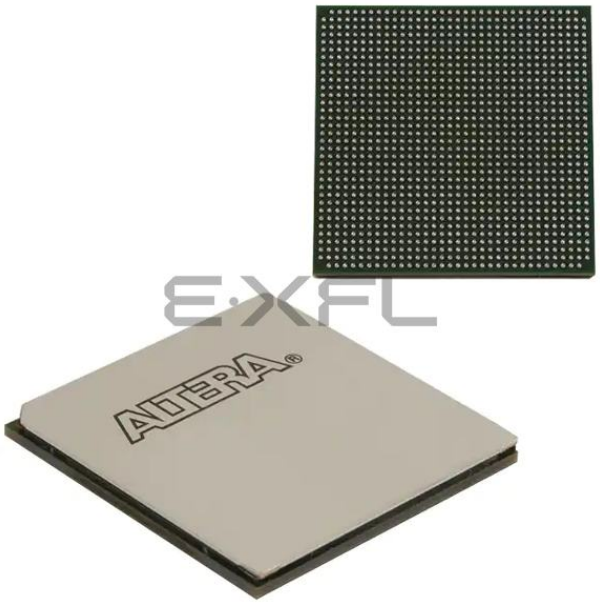
Intel - EP2AGZ350FF35C3N Datasheet



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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	13940
Number of Logic Elements/Cells	348500
Total RAM Bits	21270528
Number of I/O	554
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1152-BBGA, FCBGA
Supplier Device Package	1152-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2agz350ff35c3n

CAUTION

Conditions beyond those listed in Table 1–1 and Table 1–2 may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Table 1–1 lists the absolute maximum ratings for Arria II GX devices.

Table 1–1. Absolute Maximum Ratings for Arria II GX Devices

Symbol	Description	Minimum	Maximum	Unit
V_{CC}	Supplies power to the core, periphery, I/O registers, PCI Express® (PIPE) (PCIe) HIP block, and transceiver PCS	–0.5	1.35	V
V_{CCCB}	Supplies power for the configuration RAM bits	–0.5	1.8	V
V_{CCBAT}	Battery back-up power supply for design security volatile key register	–0.5	3.75	V
V_{CCPD}	Supplies power to the I/O pre-drivers, differential input buffers, and MSEL circuitry	–0.5	3.75	V
V_{CCIO}	Supplies power to the I/O banks	–0.5	3.9	V
V_{CCD_PLL}	Supplies power to the digital portions of the PLL	–0.5	1.35	V
V_{CCA_PLL}	Supplies power to the analog portions of the PLL and device-wide power management circuitry	–0.5	3.75	V
V_I	DC input voltage	–0.5	4.0	V
I_{OUT}	DC output current, per pin	–25	40	mA
V_{CCA}	Supplies power to the transceiver PMA regulator	—	3.75	V
V_{CCL_GXB}	Supplies power to the transceiver PMA TX, PMA RX, and clocking	—	1.21	V
V_{CCH_GXB}	Supplies power to the transceiver PMA output (TX) buffer	—	1.8	V
T_J	Operating junction temperature	–55	125	°C
T_{STG}	Storage temperature (no bias)	–65	150	°C

Table 1–2 lists the absolute maximum ratings for Arria II GZ devices.

Table 1–2. Absolute Maximum Ratings for Arria II GZ Devices (Part 1 of 2)

Symbol	Description	Minimum	Maximum	Unit
V_{CC}	Supplies power to the core, periphery, I/O registers, PCIe HIP block, and transceiver PCS	-0.5	1.35	V
V_{CCCB}	Power supply to the configuration RAM bits	-0.5	1.8	V
V_{CCPGM}	Supplies power to the configuration pins	-0.5	3.75	V
V_{CCAUX}	Auxiliary supply	-0.5	3.75	V
V_{CCBAT}	Supplies battery back-up power for design security volatile key register	-0.5	3.75	V
V_{CCPD}	Supplies power to the I/O pre-drivers, differential input buffers, and MSEL circuitry	-0.5	3.75	V
V_{CCIO}	Supplies power to the I/O banks	-0.5	3.9	V
V_{CC_CLKIN}	Supplies power to the differential clock input	-0.5	3.75	V
V_{CCD_PLL}	Supplies power to the digital portions of the PLL	-0.5	1.35	V
V_{CCA_PLL}	Supplies power to the analog portions of the PLL and device-wide power management circuitry	-0.5	3.75	V
V_I	DC input voltage	-0.5	4.0	V
I_{OUT}	DC output current, per pin	-25	40	mA

Table 1–3. Maximum Allowed Overshoot During Transitions for Arria II Devices

Symbol	Description	Condition (V)	Overshoot Duration as % of High Time	Unit
V_I (AC)	AC Input Voltage	4.0	100.000	%
		4.05	79.330	%
		4.1	46.270	%
		4.15	27.030	%
		4.2	15.800	%
		4.25	9.240	%
		4.3	5.410	%
		4.35	3.160	%
		4.4	1.850	%
		4.45	1.080	%
		4.5	0.630	%
		4.55	0.370	%
		4.6	0.220	%

Maximum Allowed I/O Operating Frequency

Table 1–4 lists the maximum allowed I/O operating frequency for Arria II GX I/Os using the specified I/O standards to ensure device reliability.

Table 1–4. Maximum Allowed I/O Operating Frequency for Arria II GX Devices

I/O Standard	I/O Frequency (MHz)
HSTL-18 and HSTL-15	333
SSTL -15	400
SSTL-18	333
2.5-V LVCMOS	260
3.3-V and 3.0-V LVTTL	250
3.3-V, 3.0-V, 1.8-V, and 1.5-V LVCMOS	
PCI and PCI-X	
SSTL-2	
1.2-V LVCMOS HSTL-12	200

Recommended Operating Conditions

This section lists the functional operation limits for AC and DC parameters for Arria II GX and GZ devices. All supplies are required to monotonically reach their full-rail values without plateaus within t_{RAMP}.

Table 1–5 lists the recommended operating conditions for Arria II GX devices.

Table 1–5. Recommended Operating Conditions for Arria II GX Devices *(Note 1)* (Part 1 of 2)

Symbol	Description	Condition	Minimum	Typical	Maximum	Unit
V_{CC}	Supplies power to the core, periphery, I/O registers, PCIe HIP block, and transceiver PCS	—	0.87	0.90	0.93	V
V_{CCCB}	Supplies power to the configuration RAM bits	—	1.425	1.50	1.575	V
V_{CCBAT} *(2)*	Battery back-up power supply for design security volatile key registers	—	1.2	—	3.3	V
V_{CCPD} *(3)*	Supplies power to the I/O pre-drivers, differential input buffers, and MSEL circuitry	—	3.135	3.3	3.465	V
		—	2.85	3.0	3.15	V
		—	2.375	2.5	2.625	V
V_{CCIO}	Supplies power to the I/O banks *(4)*	—	3.135	3.3	3.465	V
		—	2.85	3.0	3.15	V
		—	2.375	2.5	2.625	V
		—	1.71	1.8	1.89	V
		—	1.425	1.5	1.575	V
		—	1.14	1.2	1.26	V
V_{CCD_PLL}	Supplies power to the digital portions of the PLL	—	0.87	0.90	0.93	V
V_{CCA_PLL}	Supplies power to the analog portions of the PLL and device-wide power management circuitry	—	2.375	2.5	2.625	V
V_I	DC Input voltage	—	–0.5	—	3.6	V
V_O	Output voltage	—	0	—	V_{CCIO}	V
V_{CCA}	Supplies power to the transceiver PMA regulator	—	2.375	2.5	2.625	V
V_{CCL_GXB}	Supplies power to the transceiver PMA TX, PMA RX, and clocking	—	1.045	1.1	1.155	V
V_{CCH_GXB}	Supplies power to the transceiver PMA output (TX) buffer	—	1.425	1.5	1.575	V
T_J	Operating junction temperature	Commercial	0	—	85	°C
		Industrial	–40	—	100	°C

The calibration accuracy for calibrated series and parallel OCTs are applicable at the moment of calibration. When process, voltage, and temperature (PVT) conditions change after calibration, the tolerance may change.

Table 1–13 lists the Arria II GZ OCT without calibration resistance tolerance to PVT changes.

Table 1–13. OCT Without Calibration Resistance Tolerance Specifications for Arria II GZ Devices

Symbol	Description	Conditions (V)	Resistance Tolerance		Unit
			C3,I3	C4,I4	
25-Ω R_S 3.0 and 2.5	25-Ω internal series OCT without calibration	V_{CCIO} = 3.0, 2.5	± 40	± 40	%
25-Ω R_S 1.8 and 1.5	25-Ω internal series OCT without calibration	V_{CCIO} = 1.8, 1.5	± 40	± 40	%
25-Ω R_S 1.2	25-Ω internal series OCT without calibration	V_{CCIO} = 1.2	± 50	± 50	%
50-Ω R_S 3.0 and 2.5	50-Ω internal series OCT without calibration	V_{CCIO} = 3.0, 2.5	± 40	± 40	%
50-Ω R_S 1.8 and 1.5	50-Ω internal series OCT without calibration	V_{CCIO} = 1.8, 1.5	± 40	± 40	%
50-Ω R_S 1.2	50-Ω internal series OCT without calibration	V_{CCIO} = 1.2	± 50	± 50	%
100-Ω R_D 2.5	100-Ω internal differential OCT	V_{CCIO} = 2.5	± 25	± 25	%

OCT calibration is automatically performed at power up for OCT-enabled I/Os. When voltage and temperature conditions change after calibration, the resistance may change. Use Equation 1–1 and Table 1–14 to determine the OCT variation when voltage and temperature vary after power-up calibration for Arria II GX and GZ devices.

Equation 1–1. OCT Variation ***(Note 1)***

$$R_{OCT} = R_{SCAL}\left(1 + \langle\frac{dR}{dT} \times \Delta T\rangle \pm \langle\frac{dR}{dV} \times \Delta V\rangle\right)$$

Notes to Equation 1–1:

(1) R_{OCT} value calculated from Equation 1–1shows the range of OCT resistance with the variation of temperature and V_{CCIO}.

Table 1–19 lists the weak pull-up resistor values for Arria II GZ devices.

Table 1–19. Internal Weak Pull-Up Resistor for Arria II GZ Devices *(Note 1)*, *(2)*

Symbol	Description	Conditions	Min	Typ	Max	Unit
R_{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if the programmable pull-up resistor option is enabled.	V_{CCIO} = 3.0 V ±5% *(3)*	—	25	—	kΩ
		V_{CCIO} = 2.5 V ±5% *(3)*	—	25	—	kΩ
		V_{CCIO} = 1.8 V ±5% *(3)*	—	25	—	kΩ
		V_{CCIO} = 1.5 V ±5% *(3)*	—	25	—	kΩ
		V_{CCIO} = 1.2 V ±5% *(3)*	—	25	—	kΩ

Notes to Table 1–19:

(1) All I/O pins have an option to enable weak pull-up except configuration, test, and JTAG pins.

(2) The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 kΩ .

(3) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.

Hot Socketing

Table 1–20 lists the hot-socketing specification for Arria II GX and GZ devices.

Table 1–20. Hot Socketing Specifications for Arria II Devices

Symbol	Description	Maximum
$I_{IIOPIN(DC)}$	DC current per I/O pin	300 µA
$I_{IOPIN(AC)}$	AC current per I/O pin	8 mA *(1)*
$I_{XCVRTX(DC)}$	DC current per transceiver TX pin	100 mA
$I_{XCVRRX(DC)}$	DC current per transceiver RX pin	50 mA

Note to Table 1–20:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{IOPIN}|$ = C dv/dt, in which "C" is I/O pin capacitance and "dv/dt" is slew rate.

Schmitt Trigger Input

The Arria II GX device supports Schmitt trigger input on the TDI, TMS, TCK, nSTATUS, nCONFIG, nCE, CONF_DONE, and DCLK pins. A Schmitt trigger feature introduces hysteresis to the input signal for improved noise immunity, especially for signals with slow edge rates.

Table 1–21 lists the hysteresis specifications across the supported V_{CCIO} range for Schmitt trigger inputs in Arria II GX devices.

Table 1–21. Schmitt Trigger Input Hysteresis Specifications for Arria II GX Devices

Symbol	Description	Condition (V)	Minimum	Unit
$V_{Schmitt}$	Hysteresis for Schmitt trigger input	V_{CCIO} = 3.3	220	mV
		V_{CCIO} = 2.5	180	mV
		V_{CCIO} = 1.8	110	mV
		V_{CCIO} = 1.5	70	mV

I/O Standard Specifications

Table 1–22 through Table 1–35 list input voltage (V_{IH} and V_{IL}), output voltage (V_{OH} and V_{OL}), and current drive characteristics (I_{OH} and I_{OL}) for various I/O standards supported by the Arria II device family. They also show the Arria II device family I/O standard specifications. V_{OL} and V_{OH} values are valid at the corresponding I_{OH} and I_{OL}, respectively.

For an explanation of terms used in Table 1–22 through Table 1–35, refer to "Glossary" on page 1–74.

Table 1–22 lists the single-ended I/O standards for Arria II GX devices.

Table 1–22. Single-Ended I/O Standards for Arria II GX Devices

I/O Standard	V_{CCIO} (V)			V_{IL} (V)		V_{IH} (V)		V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Typ	Max	Min	Max	Min	Max	Max	Min		
3.3 V LVTTL	3.135	3.3	3.465	–0.3	0.8	1.7	3.6	0.45	2.4	4	–4
3.3 V LVCMOS	3.135	3.3	3.465	–0.3	0.8	1.7	3.6	0.2	V_{CCIO} -0.2	2	–2
3.0 V LVTTL	2.85	3	3.15	–0.3	0.8	1.7	V_{CCIO} + 0.3	0.45	2.4	4	–4
3.0 V LVCMOS	2.85	3	3.15	–0.3	0.8	1.7	V_{CCIO} + 0.3	0.2	V_{CCIO} - 0.2	0.1	–0.1
2.5 V LVCMOS	2.375	2.5	2.625	–0.3	0.7	1.7	V_{CCIO} + 0.3	0.4	2	1	–1
1.8 V LVCMOS	1.71	1.8	1.89	–0.3	0.35 × V_{CCIO}	0.65 × V_{CCIO}	V_{CCIO} + 0.3	0.45	V_{CCIO} - 0.45	2	–2
1.5 V LVCMOS	1.425	1.5	1.575	–0.3	0.35 × V_{CCIO}	0.65 × V_{CCIO}	V_{CCIO} + 0.3	0.25 × V_{CCIO}	0.75 × V_{CCIO}	2	–2
1.2 V LVCMOS	1.14	1.2	1.26	–0.3	0.35 × V_{CCIO}	0.65 × V_{CCIO}	V_{CCIO} + 0.3	0.25 × V_{CCIO}	0.75 × V_{CCIO}	2	–2
3.0-V PCI	2.85	3	3.15	—	0.3 × V_{CCIO}	0.5 × V_{CCIO}	V_{CCIO} + 0.3	0.1 × V_{CCIO}	0.9 × V_{CCIO}	1.5	–0.5
3.0-V PCI-X	2.85	3	3.15	—	0.35 × V_{CCIO}	0.5 × V_{CCIO}	V_{CCIO} + 0.3	0.1 × V_{CCIO}	0.9 × V_{CCIO}	1.5	–0.5

Table 1–23 lists the single-ended I/O standards for Arria II GZ devices.

Table 1–23. Single-Ended I/O Standards for Arria II GZ Devices (Part 1 of 2)

I/O Standard	V_{CCIO} (V)			V_{IL} (V)		V_{IH} (V)		V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Typ	Max	Min	Max	Min	Max	Max	Min		
LVTTL	2.85	3	3.15	-0.3	0.8	1.7	3.6	0.4	2.4	2	-2
LVCMOS	2.85	3	3.15	-0.3	0.8	1.7	3.6	0.2	V_{CCIO} - 0.2	0.1	-0.1
2.5 V	2.375	2.5	2.625	-0.3	0.7	1.7	3.6	0.4	2	1	-1
1.8 V	1.71	1.8	1.89	-0.3	0.35 × V_{CCIO}	0.65 × V_{CCIO}	V_{CCIO} + 0.3	0.45	V_{CCIO} - 0.45	2	-2
1.5 V	1.425	1.5	1.575	-0.3	0.35 × V_{CCIO}	0.65 × V_{CCIO}	V_{CCIO} + 0.3	0.25 × V_{CCIO}	0.75 × V_{CCIO}	2	-2

Table 1–30 lists the HSTL I/O standards for Arria II GX devices.

Table 1–30. Differential HSTL I/O Standards for Arria II GX Devices

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I	1.71	1.8	1.89	0.2	—	0.85	—	0.95	0.88	—	0.95	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.71	—	0.79	0.71	—	0.79	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	—	—	0.5 × V_{CCIO}	—	0.48 × V_{CCIO}	0.5 × V_{CCIO}	0.52 × V_{CCIO}	0.3	—

Table 1–31 lists the HSTL I/O standards for Arria II GZ devices.

Table 1–31. Differential HSTL I/O Standards for Arria II GZ Devices

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I	1.71	1.8	1.89	0.2	—	0.78	—	1.12	0.78	—	1.12	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.68	—	0.9	0.68	—	0.9	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V_{CCIO} + 0.3	—	0.5 × V_{CCIO}	—	0.4 × V_{CCIO}	0.5 × V_{CCIO}	0.6 × V_{CCIO}	0.3	V_{CCIO} + 0.48

Table 1–32 lists the differential I/O standard specifications for Arria II GX devices.

Table 1–32. Differential I/O Standard Specifications for Arria II GX Devices *(Note 1)*

I/O Standard	V_{CCIO} (V)			V_{ID} (mV)			V_{ICM} (V) *(2)*		V_{OD} (V) *(3)*			V_{OCM} (V)		
	Min	Typ	Max	Min	Cond.	Max	Min	Max	Min	Typ	Max	Min	Typ	Max
2.5 V LVDS	2.375	2.5	2.625	100	V_{CM} = 1.25 V	—	0.05	1.80	0.247	—	0.6	1.125	1.25	1.375
RSDS *(4)*	2.375	2.5	2.625	—	—	—	—	—	0.1	0.2	0.6	0.5	1.2	1.4
Mini-LVDS *(4)*	2.375	2.5	2.625	—	—	—	—	—	0.25	—	0.6	1	1.2	1.4
LVPECL *(5)*	2.375	2.5	2.625	300	—	—	0.6	1.8	—	—	—	—	—	—
BLVDS *(6)*	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—

Notes to Table 1–32:

(1) The 1.5 V PCML transceiver I/O standard specifications are described in "Transceiver Performance Specifications" on page 1–21.
(2) V_{IN} range: 0 <= V_{IN} <= 1.85 V.
(3) R_L range: 90 <= RL <= 110 Ω.
(4) The RSDS and mini-LVDS I/O standards are only supported for differential outputs.
(5) The LVPECL input standard is supported at the dedicated clock input pins (GCLK) only.
(6) There are no fixed V_{ICM}, V_{OD}, and V_{OCM} specifications for BLVDS. These specifications depend on the system topology.

Table 1–35. Transceiver Specifications for Arria II GZ Devices (Part 2 of 5)

Symbol/ Description	Conditions	–C3 and –I3 *(1)*			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Transceiver Clocks								
Calibration block clock frequency (cal_blk_clk)	—	10	—	125	10	—	125	MHz
fixedclk clock frequency	PCIe Receiver Detect	—	125	—	—	125	—	MHz
reconfig_clk clock frequency	Dynamic reconfiguration clock frequency	2.5/ 37.5 *(4)*	—	50	2.5/ 37.5 *(4)*	—	50	MHz
Delta time between reconfig_clks *(5)*	—	—	—	2	—	—	2	ms
Transceiver block minimum power-down (gxb_powerdown) pulse width	—	1	—	—	1	—	—	µs
Receiver								
Supported I/O Standards	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS							
Data rate *(16)*	—	600	—	6375	600	—	3750	Mbps
Absolute V_{MAX} for a receiver pin *(6)*	—	—	—	1.6	—	—	1.6	V
Operational V_{MAX} for a receiver pin	—	—	—	1.5	—	—	1.5	V
Absolute V_{MIN} for a receiver pin	—	-0.4	—	—	-0.4	—	—	V
Maximum peak-to-peak differential input voltage V_{ID} (diff p-p) before device configuration	—	—	—	1.6	—	—	1.6	V
Maximum peak-to-peak differential input voltage V_{ID} (diff p-p) after device configuration	V_{ICM} = 0.82 V setting	—	—	2.7	—	—	2.7	V
	V_{ICM} =1.1 V setting *(7)*	—	—	1.6	—	—	1.6	V
Minimum differential eye opening at receiver serial input pins *(8)*	Data Rate = 600 Mbps to 5 Gbps Equalization = 0 DC gain = 0 dB	100	—	—	165	—	—	mV
	Data Rate > 5 Gbps Equalization = 0 DC gain = 0 dB	165	—	—	165	—	—	mV
V_{ICM}	V_{ICM} = 0.82 V setting	820 ± 10%			820 ± 10%			mV
	V_{ICM} = 1.1 V setting *(7)*	1100 ± 10%			1100 ± 10%			mV

Table 1–35. Transceiver Specifications for Arria II GZ Devices (Part 4 of 5)

Symbol/ Description	Conditions	–C3 and –I3 *(1)*			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Transmitter								
Supported I/O Standards	1.5-V PCML							
Data rate *(14)*	—	600	—	6375	600	—	3750	Mbps
V_{OCM}	0.65 V setting	—	650	—	—	650	—	mV
Differential on-chip termination resistors	85–Ω setting	85 ± 15%			85 ± 15%			Ω
	100–Ω setting	100 ± 15%			100 ± 15%			Ω
	120–Ω setting	120 ± 15%			120 ± 15%			Ω
	150-Ω setting	150 ± 15%			150 ± 15%			Ω
Differential and common mode return loss	PCIe Gen1 and Gen2 (TX V_{OD}=4), XAUI (TX V_{OD}=6), HiGig+ (TX V_{OD}=6), CEI SR/LR (TX V_{OD}=8), SRIO SR (V_{OD}=6), SRIO LR (V_{OD}=8), CPRI LV (V_{OD}=6), CPRI HV (V_{OD}=2), OBSAI (V_{OD}=6), SATA (V_{OD}=4),	Compliant						—
Rise time *(15)*	—	50	—	200	50	—	200	ps
Fall time *(15)*	—	50	—	200	50	—	200	ps
Intra-differential pair skew	—	—	—	15	—	—	15	ps
Intra-transceiver block transmitter channel-to-channel skew	×4 PMA and PCS bonded mode Example: XAUI, PCIe ×4, Basic ×4	—	—	120	—	—	120	ps
Inter-transceiver block transmitter channel-to-channel skew	×8 PMA and PCS bonded mode Example: PCIe ×8, Basic ×8	—	—	500	—	—	500	ps
CMU0 PLL and CMU1 PLL								
Supported Data Range	—	600	—	6375	600	—	3750	Mbps
`pll_powerdown` minimum pulse width (`tpll_powerdown`)	—	1			1			µs
CMU PLL lock time from `pll_powerdown` de-assertion	—	—	—	100	—	—	100	µs

Table 1–37 lists the typical V_{OD} for TX term that equals 100 Ω for Arria II GX and GZ devices.

Table 1–37. Typical V_{OD} Setting, TX Termination = 100 Ω for Arria II Devices

Quartus II Setting	V_{OD} Setting (mV)
1	400
2	600
3 (Arria II GZ)	700
4	800
5	900
6	1000
7	1200

Table 1–38 lists the typical transmitter pre-emphasis levels in dB for the first post tap under the following conditions: low-frequency data pattern (five 1s and five 0s) at 6.375 Gbps. The levels listed in Table 1–38 are a representation of possible pre-emphasis levels under these specified conditions only, the pre-emphasis levels may change with data pattern and data rate.

To predict the pre-emphasis level for your specific data rate and pattern, run simulations using the Arria II GX HSSI HSPICE models.

Table 1–38. Transmitter Pre-Emphasis Levels for Arria II GX Devices

Arria II GX (Quartus II Software) First Post Tap Setting	Arria II GX (Quartus II Software) VOD Setting						
	1	2	4	5	6	7	Unit
0 (off)	0	0	0	0	0	0	—
1	0.7	0	0	0	0	0	dB
2	2.7	1.2	0.3	0	0	0	dB
3	4.9	2.4	1.2	0.8	0.5	0.2	dB
4	7.5	3.8	2.1	1.6	1.2	0.6	dB
5	—	5.3	3.1	2.4	1.8	1.1	dB
6	—	7	4.3	3.3	2.7	1.7	dB

Table 1–39. Transmitter Pre-Emphasis Levels for Arria II GZ Devices (Part 2 of 2)

Pre-Emphasis 1st Post-Tap Setting	V_{OD} Setting							
	0	1	2	3	4	5	6	7
29	N/A	N/A	N/A	12.5	9.6	7.7	6.3	4.3
30	N/A	N/A	N/A	N/A	11.4	9	7.4	N/A
31	N/A	N/A	N/A	N/A	12.9	10	8.2	N/A

Table 1–40 lists the transceiver jitter specifications for all supported protocols for Arria II GX devices.

Table 1–40. Transceiver Block Jitter Specifications for Arria II GX Devices *(Note 1)* (Part 1 of 10)

Symbol/ Description	Conditions	I3			C4			C5, I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
SONET/SDH Transmit Jitter Generation *(2)*														
Peak-to-peak jitter at 622.08 Mbps	Pattern = PRBS15	—	—	0.1	—	—	0.1	—	—	0.1	—	—	0.1	UI
RMS jitter at 622.08 Mbps	Pattern = PRBS15	—	—	0.01	—	—	0.01	—	—	0.01	—	—	0.01	UI
Peak-to-peak jitter at 2488.32 Mbps	Pattern = PRBS15	—	—	0.1	—	—	0.1	—	—	0.1	—	—	0.1	UI
RMS jitter at 2488.32 Mbps	Pattern = PRBS15	—	—	0.01	—	—	0.01	—	—	0.01	—	—	0.01	UI
SONET/SDH Receiver Jitter Tolerance *(2)*														
Jitter tolerance at 622.08 Mbps	Jitter frequency = 0.03 KHz Pattern = PRBS15	> 15			> 15			> 15			> 15			UI
	Jitter frequency = 25 KHZ Pattern = PRBS15	> 1.5			> 1.5			> 1.5			> 1.5			UI
	Jitter frequency = 250 KHz Pattern = PRBS15	> 0.15			> 0.15			> 0.15			> 0.15			UI

Table 1–40. Transceiver Block Jitter Specifications for Arria II GX Devices *(Note 1)* (Part 2 of 10)

Symbol/ Description	Conditions	I3			C4			C5, I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Jitter tolerance at 2488.32 Mbps	Jitter frequency = 0.06 KHz Pattern = PRBS15		> 15			> 15			> 15			> 15		UI
	Jitter frequency = 100 KHZ Pattern = PRBS15		> 1.5			> 1.5			> 1.5			> 1.5		UI
	Jitter frequency = 1 MHz Pattern = PRBS15		> 0.15			> 0.15			> 0.15			> 0.15		UI
	Jitter frequency = 10 MHz Pattern = PRBS15		> 0.15			> 0.15			> 0.15			> 0.15		UI
XAUI Transmit Jitter Generation *(3)*														
Total jitter at 3.125 Gbps	Pattern = CJPAT	—	—	0.3	—	—	0.3	—	—	0.3	—	—	0.3	UI
Deterministic jitter at 3.125 Gbps	Pattern = CJPAT	—	—	0.17	—	—	0.17	—	—	0.17	—	—	0.17	UI
XAUI Receiver Jitter Tolerance *(3)*														
Total jitter	—		> 0.65			> 0.65			> 0.65			> 0.65		UI
Deterministic jitter	—		> 0.37			> 0.37			> 0.37			> 0.37		UI
Peak-to-peak jitter	Jitter frequency = 22.1 KHz		> 8.5			> 8.5			> 8.5			> 8.5		UI
Peak-to-peak jitter	Jitter frequency = 1.875 MHz		> 0.1			> 0.1			> 0.1			> 0.1		UI
Peak-to-peak jitter	Jitter frequency = 20 MHz		> 0.1			> 0.1			> 0.1			> 0.1		UI
PCIe Transmit Jitter Generation *(4)*														
Total jitter at 2.5 Gbps (Gen1)	Compliance pattern	—	—	0.25	—	—	0.25	—	—	0.25	—	—	0.25	UI

Table 1–41. Transceiver Block Jitter Specifications for Arria II GZ Devices *(Note 1)*, *(2)* (Part 5 of 7)

Symbol/ Description	Conditions	–C3 and –I3			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Sinusoidal jitter tolerance (peak-to-peak)	Jitter Frequency = 38.2 KHz Data rate = 6.375 Gbps Pattern = PRBS31 BER = 10^{-12}	> 0.5			—	—	—	UI
	Jitter Frequency = 3.82 MHz Data rate = 6.375 Gbps Pattern = PRBS31 BER = 10^{-12}	> 0.05			—	—	—	UI
	Jitter Frequency = 20 MHz Data rate = 6.375 Gbps Pattern = PRBS31 BER = 10^{-12}	> 0.05			—	—	—	UI
SDI Transmitter Jitter Generation *(12)*								
Alignment jitter (peak-to-peak)	Data rate = 1.485 Gbps (HD) Pattern = color bar Low-frequency roll-off = 100 KHz	0.2	—	—	0.2	—	—	UI
	Data rate = 2.97 Gbps (3G) Pattern = color bar Low-frequency roll-off = 100 KHz	0.3	—	—	0.3	—	—	UI
SDI Receiver Jitter Tolerance *(12)*								
Sinusoidal jitter tolerance (peak-to-peak)	Jitter frequency = 15 KHz Data rate = 2.97 Gbps (3G) Pattern = single line scramble color bar	> 2			> 2			UI
	Jitter frequency = 100 KHz Data rate = 2.97 Gbps (3G) Pattern = single line scramble color bar	> 0.3			> 0.3			UI
	Jitter frequency = 148.5 MHz Data rate = 2.97 Gbps (3G) Pattern = single line scramble color bar	> 0.3			> 0.3			UI
Sinusoidal jitter tolerance (peak-to-peak)	Jitter frequency = 20 KHz Data rate = 1.485 Gbps (HD) pattern = 75% color bar	> 1			> 1			UI
	Jitter frequency = 100 KHz Data rate = 1.485 Gbps (HD) Pattern = 75% color bar	> 0.2			> 0.2			UI
	Jitter frequency = 148.5 MHz Data rate = 1.485 Gbps (HD) Pattern = 75% color bar	> 0.2			> 0.2			UI
SAS Transmit Jitter Generation *(13)*								
Total jitter at 1.5 Gbps (G1)	Pattern = CJPAT	—	—	0.55	—	—	0.55	UI
Deterministic jitter at 1.5 Gbps (G1)	Pattern = CJPAT	—	—	0.35	—	—	0.35	UI
Total jitter at 3.0 Gbps (G2)	Pattern = CJPAT	—	—	0.55	—	—	0.55	UI

Table 1–44. PLL Specifications for Arria II GX Devices (Part 2 of 3)

Symbol	Description	Min	Typ	Max	Unit
f_{OUT}	Output frequency for internal global or regional clock (–4 Speed Grade)	—	—	500	MHz
	Output frequency for internal global or regional clock (–5 Speed Grade)	—	—	500	MHz
	Output frequency for internal global or regional clock (–6 Speed Grade)	—	—	400	MHz
f_{OUT_EXT}	Output frequency for external clock output (–4 Speed Grade)	—	—	670 *(5)*	MHz
	Output frequency for external clock output (–5 Speed Grade)	—	—	622 *(5)*	MHz
	Output frequency for external clock output (–6 Speed Grade)	—	—	500 *(5)*	MHz
$t_{OUTDUTY}$	Duty cycle for external clock output (when set to 50%)	45	50	55	%
t_{OUTPJ_DC}	Dedicated clock output period jitter ($f_{OUT} \geq 100$ MHz)	—	—	300	ps (p–p)
	Dedicated clock output period jitter ($f_{OUT} < 100$ MHz)	—	—	30	mUI (p–p)
t_{OUTCCJ_DC}	Dedicated clock output cycle-to-cycle jitter ($f_{OUT} \geq 100$ MHz)	—	—	300	ps (p–p)
	Dedicated clock output cycle-to-cycle jitter ($f_{OUT} < 100$ MHz)	—	—	30	mUI (p–p)
f_{OUTPJ_IO}	Regular I/O clock output period jitter ($f_{OUT} \geq 100$ MHz)	—	—	650	ps (p–p)
	Regular I/O clock output period jitter ($f_{OUT} < 100$ MHz)	—	—	65	mUI (p–p)
f_{OUTCCJ_IO}	Regular I/O clock output cycle-to-cycle jitter ($f_{OUT} \geq 100$ MHz)	—	—	650	ps (p–p)
	Regular I/O clock output cycle-to-cycle jitter ($f_{OUT} < 100$ MHz)	—	—	65	mUI (p–p)
$t_{CONFIGPLL}$	Time required to reconfigure PLL scan chains	—	3.5	—	SCANCLK cycles
$t_{CONFIGPHASE}$	Time required to reconfigure phase shift	—	1	—	SCANCLK cycles
$f_{SCANCLK}$	SCANCLK frequency	—	—	100	MHz
t_{LOCK}	Time required to lock from end of device configuration	—	—	1	ms
t_{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)	—	—	1	ms
f_{CLBW}	PLL closed-loop low bandwidth	—	0.3	—	MHz
	PLL closed-loop medium bandwidth	—	1.5	—	MHz
	PLL closed-loop high bandwidth	—	4	—	MHz
t_{PLL_PSERR}	Accuracy of PLL phase shift	—	—	±50	ps
t_{ARESET}	Minimum pulse width on `areset` signal	10	—	—	ns

Configuration

Table 1–50 lists the configuration mode specifications for Arria II GX and GZ devices.

Table 1–50. Configuration Mode Specifications for Arria II Devices

Programming Mode	DCLK Frequency			Unit
	Min	Typ	Max	
Passive serial	—	—	125	MHz
Fast passive parallel	—	—	125	MHz
Fast active serial (fast clock)	17	26	40	MHz
Fast active serial (slow clock)	8.5	13	20	MHz
Remote update only in fast AS mode	—	—	10	MHz

JTAG Specifications

Table 1–51 lists the JTAG timing parameters and values for Arria II GX and GZ devices.

Table 1–51. JTAG Timing Parameters and Values for Arria II Devices

Symbol	Description	Min	Max	Unit
t_{JCP}	TCK clock period	30	—	ns
t_{JCH}	TCK clock high time	14	—	ns
t_{JCL}	TCK clock low time	14	—	ns
$t_{JPSU\ (TDI)}$	TDI JTAG port setup time	1	—	ns
$t_{JPSU\ (TMS)}$	TMS JTAG port setup time	3	—	ns
t_{JPH}	JTAG port hold time	5	—	ns
t_{JPCO}	JTAG port clock to output	—	11	ns
t_{JPZX}	JTAG port high impedance to valid output	—	14	ns
t_{JPXZ}	JTAG port valid output to high impedance	—	14	ns

Chip-Wide Reset (Dev_CLRn) Specifications

Table 1–52 lists the specifications for the chip-wide reset (Dev_CLRn) for Arria II GX and GZ devices.

Table 1–52. Chip-Wide Reset (Dev_CLRn) Specifications for Arria II Devices

Description	Min	Typ	Max	Unit
Dev_CLRn	500	—	—	µs

Table 1–53. High-Speed I/O Specifications for Arria II GX Devices (Part 2 of 4)

Symbol	Conditions	I3		C4		C5,I5		C6		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
Transmitter										
f_{HSDR_TX} (true LVDS output data rate)	SERDES factor, J = 3 to 10 (using dedicated SERDES)	150	1250 *(2)*	150	1250 *(2)*	150	1050 *(2)*	150	840	Mbps
	SERDES factor, J = 4 to 10 (using logic elements as SERDES)	*(3)*	945	*(3)*	945	*(3)*	840	*(3)*	740	Mbps
	SERDES factor, J = 2 (using DDR registers) and J = 1 (using SDR register)	*(3)*	*(3)*	*(3)*	*(3)*	*(3)*	*(3)*	*(3)*	*(3)*	Mbps
$f_{HSDR\_TX\_E3R}$ (emulated LVDS_E_3R output data rate) *(7)*	SERDES factor, J = 4 to 10	*(3)*	945	*(3)*	945	*(3)*	840	*(3)*	740	Mbps

Table 1–53. High-Speed I/O Specifications for Arria II GX Devices (Part 4 of 4)

Symbol	Conditions	I3		C4		C5,I5		C6		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
f_{HSDR} (data rate)	SERDES factor J = 3 to 10	*(3)*	945 *(7)*	*(3)*	945 *(7)*	*(3)*	740 *(7)*	*(3)*	640 *(7)*	Mbps
	SERDES factor J = 2 (using DDR registers)	*(3)*	*(7)*	*(3)*	*(7)*	*(3)*	*(7)*	*(3)*	*(7)*	Mbps
	SERDES factor J = 1 (using SDR registers)	*(3)*	*(7)*	*(3)*	*(7)*	*(3)*	*(7)*	*(3)*	*(7)*	Mbps
Soft-CDR PPM tolerance	Soft-CDR mode	—	300	—	300	—	300	—	300	±PPM
DPA run length	DPA mode	—	10,000	—	10,000	—	10,000	—	10,000	UI
Sampling window (SW)	Non-DPA mode *(5)*	—	300	—	300	—	350	—	400	ps

Notes to Table 1–53:

(1) $f_{HSCLK\_IN} = f_{HSDR} / W$. Use W to determine the supported selection of input reference clock frequencies for the desired data rate.

(2) Applicable for interfacing with DPA receivers only. For interfacing with non-DPA receivers, you must calculate the leftover timing margin in the receiver by performing link timing closure analysis. For Arria II GX transmitter to Arria II GX non-DPA receiver, the maximum supported data rate is 945 Mbps. For data rates above 840 Mbps, perform PCB trace compensation by adjusting the PCB trace length for LVDS channels to improve channel-to-channel skews.

(3) The minimum and maximum specification depends on the clock source (for example, PLL and clock pin) and the clock routing resource you use (global, regional, or local). The I/O differential buffer and input register do not have a minimum toggle rate.

(4) The specification is only applicable under the influence of core noise.

(5) Applicable for true LVDS using dedicated SERDES only.

(6) Dedicated SERDES and DPA features are only available on the right banks.

(7) You must calculate the leftover timing margin in the receiver by performing link timing closure analysis. You must consider the board skew margin, transmitter channel-to-channel skew, and the receiver sampling margin to determine the leftover timing margin.

Table 1–54 lists the high-speed I/O timing for Arria II GZ devices.

Table 1–54. High-Speed I/O Specifications for Arria II GZ Devices *(Note 1), (2), (10)* (Part 1 of 3)

Symbol	Conditions	C3, I3			C4, I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Clock								
f_{HSCLK_in} (input clock frequency) true differential I/O standards	Clock boost factor W = 1 to 40 *(3)*	5	—	717	5	—	717	MHz
f_{HSCLK_in} (input clock frequency) single ended I/O standards *(9)*	Clock boost factor W = 1 to 40 *(3)*	5	—	717	5	—	717	MHz
f_{HSCLK_in} (input clock frequency) single ended I/O standards *(10)*	Clock boost factor W = 1 to 40 *(3)*	5	—	420	5	—	420	MHz

Table 1–55. DPA Lock Time Specifications for Arria II Devices *(Note 1)*, *(2)*, *(3)*

Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions *(4)*	Maximum
SPI-4	00000000001111111111	2	128	640 data transitions
Parallel Rapid I/O	00001111	2	128	640 data transitions
	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
	01010101	8	32	640 data transitions

Notes to Table 1–55:

(1) The DPA lock time is for one channel.
(2) One data transition is defined as a 0-to-1 or 1-to-0 transition.
(3) The DPA lock time stated in the table applies to both commercial and industrial grade.
(4) This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

Figure 1–5 shows the LVDS soft-CDR/DPA sinusoidal jitter tolerance specification for Arria II GZ devices at a data rate less than 1.25 Gbps and all the Arria II GX devices.

Figure 1–5. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for All Arria II GX Devices and for Arria II GZ Devices at a Data Rate less than 1.25 Gbps

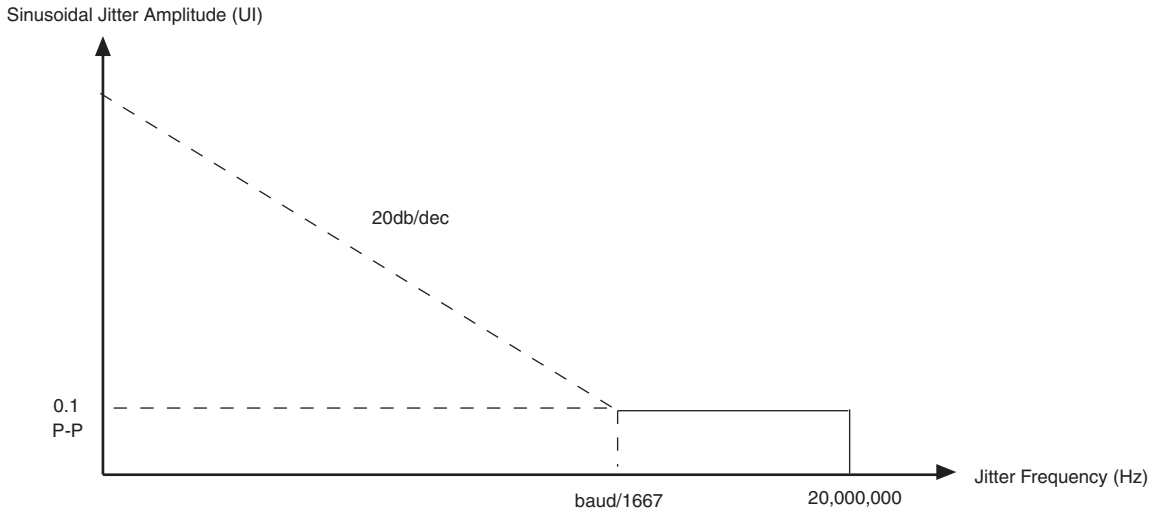

Table 1–60 lists the DQS phase shift error for Arria II GX devices.

Table 1–60. DQS Phase Shift Error Specification for DLL-Delayed Clock (t_{DQS_PSERR}) for Arria II GX Devices *(Note 1)*

Number of DQS Delay Buffer	C4	I3, C5, I5	C6	Unit
1	26	30	36	ps
2	52	60	72	ps
3	78	90	108	ps
4	104	120	144	ps

Note to Table 1–60:

(1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a C4 speed grade is ± 78 ps or ± 39 ps.

Table 1–61 lists the DQS phase shift error for Arria II GZ devices.

Table 1–61. DQS Phase Shift Error Specification for DLL-Delayed Clock (t_{DQS_PSERR}) for Arria II GZ Devices *(Note 1)*

Number of DQS Delay Buffer	–3	–4	Unit
1	28	30	ps
2	56	60	ps
3	84	90	ps
4	112	120	ps

Note to Table 1–61:

(1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a 3 speed grade is ± 84 ps or ± 42 ps.

Table 1–62 lists the memory output clock jitter specifications for Arria II GX devices.

Table 1–62. Memory Output Clock Jitter Specification for Arria II GX Devices *(Note 1)*, *(2)*, *(3)*

Parameter	Clock Network	Symbol	–4		–5		–6		Unit
			Min	Max	Min	Max	Min	Max	
Clock period jitter	Global	$t_{JIT(per)}$	-100	100	-125	125	-125	125	ps
Cycle-to-cycle period jitter	Global	$t_{JIT(cc)}$	-200	200	-250	250	-250	250	ps
Duty cycle jitter	Global	$t_{JIT(duty)}$	-100	100	-125	125	-125	125	ps

Notes to Table 1–62:

(1) The memory output clock jitter measurements are for 200 consecutive clock cycles, as specified in the JEDEC DDR2/DDR3 SDRAM standard.

(2) The clock jitter specification applies to memory output clock pins generated using DDIO circuits clocked by a PLL output routed on a global clock network.

(3) The memory output clock jitter stated in Table 1–62 is applicable when an input jitter of 30 ps is applied.

IOE Programmable Delay

Table 1–66 lists the delay associated with each supported IOE programmable delay chain for Arria II GX devices.

Table 1–66. IOE Programmable Delay for Arria II GX Devices

Parameter	Available Settings (1)	Minimum Offset (2)	Maximum Offset								Unit
			Fast Model			Slow Model					
			I3	C4	I5	I3	C4	C5	I5	C6	
Output enable pin delay	7	0	0.413	0.442	0.413	0.814	0.713	0.796	0.801	0.873	ns
Delay from output register to output pin	7	0	0.339	0.362	0.339	0.671	0.585	0.654	0.661	0.722	ns
Input delay from pin to internal cell	52	0	1.494	1.607	1.494	2.895	2.520	2.733	2.775	2.944	ns
Input delay from pin to input register	52	0	1.493	1.607	1.493	2.896	2.503	2.732	2.774	2.944	ns
DQS bus to input register delay	4	0	0.074	0.076	0.074	0.140	0.124	0.147	0.147	0.167	ns

Notes to Table 1–66:

(1) The available setting for every delay chain starts with zero and ends with the specified maximum number of settings.

(2) The minimum offset represented in the table does not include intrinsic delay.

Table 1–67 lists the IOE programmable delay settings for Arria II GZ devices.

Table 1–67. IOE Programmable Delay for Arria II GZ Devices

Parameter	Available Settings (1)	Minimum Offset (2)	Maximum Offset						Unit
			Fast Model		Slow Model				
			Industrial	Commercial	C3	I3	C4	I4	
D1	15	0	0.462	0.505	0.795	0.801	0.857	0.864	ns
D2	7	0	0.234	0.232	0.372	0.371	0.407	0.405	ns
D3	7	0	1.700	1.769	2.927	2.948	3.157	3.178	ns
D4	15	0	0.508	0.554	0.882	0.889	0.952	0.959	ns
D5	15	0	0.472	0.500	0.799	0.817	0.875	0.882	ns
D6	6	0	0.186	0.195	0.319	0.321	0.345	0.347	ns

Notes to Table 1–67:

(1) You can set this value in the Quartus II software by selecting **D1**, **D2**, **D3**, **D4**, **D5**, and **D6** in the **Assignment Name** column.

(2) Minimum offset does not include the intrinsic delay.